**Product data sheet** 

## 1. General description

Silicon Carbide MOSFET in a TSPAK plastic package with top side cooling structure, designed for high frequency, high efficiency systems.





### 2. Features and benefits

- · Top side cooling structure
- Kelvin source configuration
- Low specific on-resistance
- Optimized dynamic performance
- Robust gate design
- 0V turn-off V<sub>GS</sub> for simple gate driver
- 100% UIS Tested
- Easy to parallel
- RoHS compliant



## 3. Applications

- Switching mode power supplies
- UPS and energy storage systems
- Battery formation instrument
- PV MPPT and inverters
- EV Chargers
- Welding machines
- Motor Drives

#### 4. Quick reference data

### Table 1. Quick reference data

able 1. Qu	lick reference data						
Symbol	Parameter	Conditions	Notes	Values		Unit	
Absolute	maximum rating						
V <sub>DS</sub>	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C			1200		V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 18 V; T <sub>mb</sub> = 25 °C			24.6		Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C, T <sub>j</sub> = 175 °C			169		W
T <sub>j</sub>	junction temperature			-55 to 175		°C	
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 10 \text{ A}; T_j = 25 ^{\circ}\text{C}$		-	150	-	mΩ
		V <sub>GS</sub> = 18 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C		-	120	150	mΩ
Dynamic	characteristics						
Q <sub>G(tot)</sub>	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	40	-	nC
$Q_{GD}$	gate-drain charge	T <sub>j</sub> = 25 °C		-	9.8	-	nC
Source-d	rain diode					,	
Q <sub>r</sub>	recovered charge	$I_{SD}$ = 10 A; di/dt = 500 A/ $\mu$ s; $V_{DS}$ = 400 V; $T_{j}$ = 25 °C		-	26	-	nC
		,					

# 5. Pinning information

#### **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol			
1	G	gate	mb	D			
2	SS	source sense					
3-7	S	source		G (F)			
mb	D	mounting base; connected to drain	1 2 3 4 5 6 7	SS Sym301 S			

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WNSC2M150120TB	TSPAK	WNSC2M150120TB6J	Reel	600	TSPAKH	06-Dec-2024

# 7. Marking

### **Table 4. Marking codes**

Type number	Marking codes
WNSC2M150120TB	WNSC2M 150120TB

# 8. Limiting values

### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
$V_{DS}$	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage			-12 to 24	V
$V_{GS,op}$	gate-source voltage			-4 to 18	V
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C, T <sub>j</sub> = 175 °C		169	W
I <sub>D</sub>	drain current	V <sub>GS</sub> = 18 V; T <sub>mb</sub> = 25 °C		24.6	Α
		V <sub>GS</sub> = 18 V; T <sub>mb</sub> = 100 °C		17.4	Α
I <sub>DM</sub>	peak drain current	pulse width t <sub>p</sub> limited by T <sub>jmax</sub>	Fig.17	50	Α
Is	continuous diode current	V <sub>GS</sub> = -4 V; T <sub>mb</sub> = 25 °C		22.5	Α
I <sub>SM</sub>	pulse diode current	$V_{GS}$ = -4 V; pulse width $t_p$ limited by $T_{jmax}$		50	А
E <sub>as</sub>	single pulse drain-to- source avalanche	$I_{AS} = 7 \text{ A}; L = 1 \text{ mH}; V_{DD} = 100 \text{ V};$ $T_j = 25 \text{ °C}$		24.5	mJ
T <sub>stg</sub>	storage temperature			-55 to 175	°C
T <sub>j</sub>	junction temperature			-55 to 175	°C
$T_{sld(M)}$	peak soldering temperature			245	°C

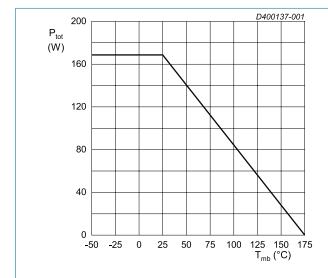


Fig. 1. Total power dissipation as a function of mounting base temperature; maximum values

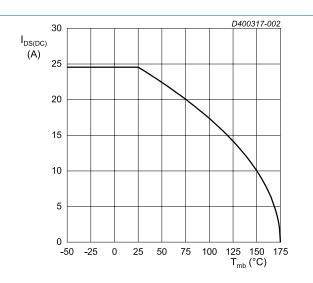


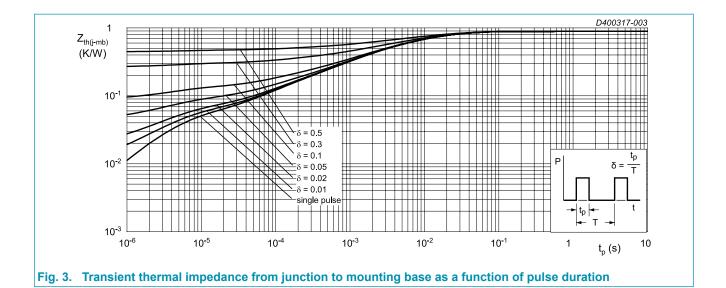
Fig. 2. Continuous Drain Current as a function of mounting base temperature

## 9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base			-	0.89	-	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air		-	40	-	K/W

Note: Device is ESD sensitive. Handling precautions are recommended.



## 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 100 \mu A; V_{GS} = 0 V; T_j = 25 ^{\circ}C$		1200	-	-	V
. ( )	gate-source threshold	$I_D = 2.5 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$		1.9	2.6	3.5	V
	voltage	$I_D = 2.5 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 175 °C$		-	1.9	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 1200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	0.2	100	μA
		V <sub>DS</sub> = 1200 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C		-	2	-	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 24 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C		-	10	100	nA
		$V_{GS} = -12 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	10	100	nA
R <sub>DS(on)</sub>	drain-source on-state	V <sub>GS</sub> = 15 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C		-	150	-	mΩ
	resistance	V <sub>GS</sub> = 18 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C		-	120	150	mΩ
		V <sub>GS</sub> = 18 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 175 °C		-	233	-	mΩ
$R_G$	gate resistance	f = 1 MHz; T <sub>j</sub> = 25 °C		-	3	-	Ω
g <sub>fs</sub>	transconductance	$V_{DS} = 20 \text{ V}; I_{D} = 10 \text{ A}; T_{j} = 25 \text{ °C}$		-	5.1	-	S
Dynamic	characteristics						
Q <sub>G(tot)</sub>	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	40	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C		-	14.5	-	nC
$Q_{GD}$	gate-drain charge			-	9.8	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS} = 1000 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$		-	741	-	pF
C <sub>oss</sub>	output capacitance			-	36	-	pF
C <sub>rss</sub>	reverse transfer capacitance			-	3.4	-	pF
E <sub>oss</sub>	Coss stored energy			-	18	-	μJ
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V}; R_{G(ext)} = 5.1$		-	17	-	ns
t <sub>r</sub>	rise time	$Ω$ ; $I_D = 10 A$ ; $L = 330 \mu H$ ; $T_j = 25 °C$		-	18	-	ns
$t_{\text{d(off)}}$	turn-off delay time			-	26	-	ns
t <sub>f</sub>	fall time			-	20	-	ns
E <sub>on</sub>	turn-on energy (Sic Diode FWD)		Fig.20	-	163	-	μJ
E <sub>off</sub>	turn-off energy (Sic Diode FWD)		Fig.20	-	15	-	μJ
E <sub>on</sub>	turn-on energy (Body Diode FWD)		Fig.20	-	158	-	μJ
E <sub>off</sub>	turn-off energy (Body Diode FWD)		Fig.20	-	18	-	μJ
Source-d	rain diode						
V <sub>SD</sub>	source-drain voltage	$V_{GS} = 0 \text{ V}; I_{SD} = 5 \text{ A}; T_j = 25 \text{ °C}$		-	3.4	-	V
		V <sub>GS</sub> = -4 V; I <sub>SD</sub> = 5 A; T <sub>j</sub> = 25 °C		-	4.8	-	V
		$V_{GS} = -4 \text{ V}; I_{SD} = 5 \text{ A}; T_j = 175 \text{ °C}$		-	4.1	-	V
t <sub>rr</sub>	reverse recovery time	$I_{SD} = 10 \text{ A}$ ; di/dt = 500 A/ $\mu$ s; $V_{DS} = 400 \text{ V}$ ;		-	17	-	ns
$Q_r$	recovered charge	T <sub>j</sub> = 25 °C		-	26	-	nC
I <sub>rrm</sub>	reverse recovery current			-	2.7	-	Α

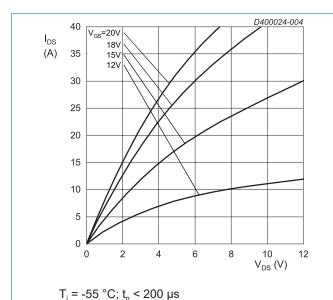
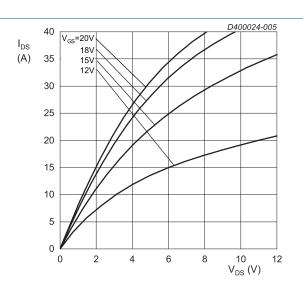
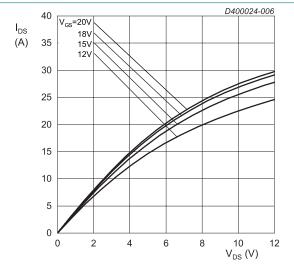


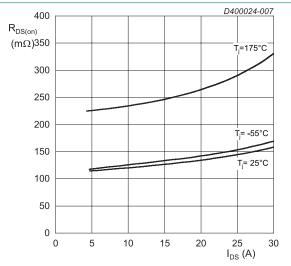
Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values



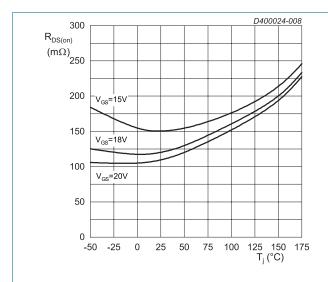
T<sub>j</sub> = 25 °C; t<sub>p</sub> < 200 μs Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



T<sub>j</sub> = 175 °C; t<sub>p</sub> < 200 μs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

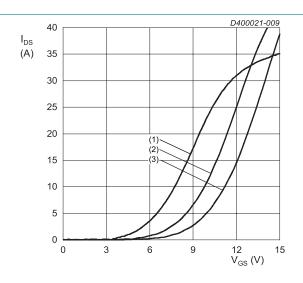


 $V_{GS}$  = 18 V;  $t_p$  < 200 µs Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



 $I_{DS}$  = 10 A;  $t_p$  < 200  $\mu s$ 

Fig. 8. Drain-source on-state resistance as a function of junction temperature

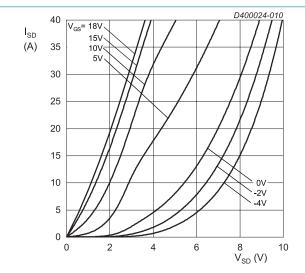


 $V_{DS}$  = 20 V;  $t_p$  < 200  $\mu s$ 

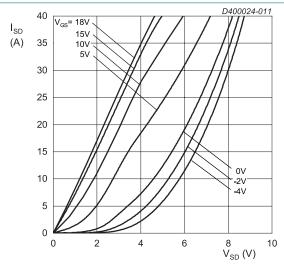
(1)  $T_j = 175 \,^{\circ}C$ (2)  $T_j = 25 \,^{\circ}C$ 

(3)  $T_i = -55 \,^{\circ}C$ 

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values

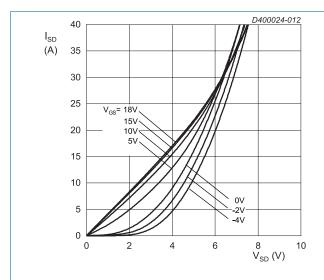


 $T_{j} = -55 \, ^{\circ}\text{C}; t_{p} < 200 \, \mu\text{s}$ Fig. 10. Body diode forward characteristics; typical values

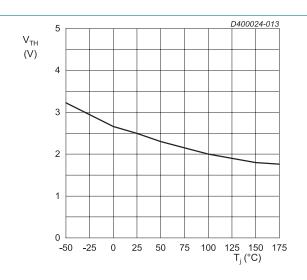


 $T_{j} = 25 \, ^{\circ}\text{C}; t_{p} < 200 \, \mu\text{s}$ 

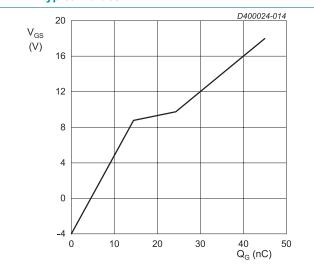
Fig. 11. Body diode forward characteristics; typical values



 $T_{j}$  = 175 °C;  $t_{p}$  < 200 µs Fig. 12. Body diode forward characteristics; typical values



V<sub>DS</sub> = 10 V; I<sub>DS</sub> = 2.5 mA Fig. 13. Threshold voltage as a function of junction temperature



I<sub>DS</sub> = 10 A; I<sub>GS</sub> = 0.1 mA; V<sub>DS</sub> = 800 V; T<sub>j</sub> = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

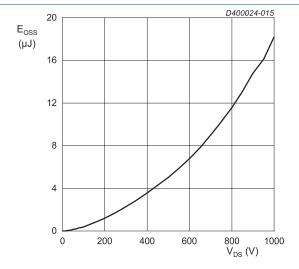
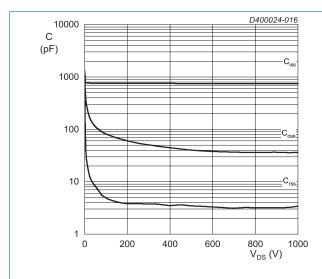
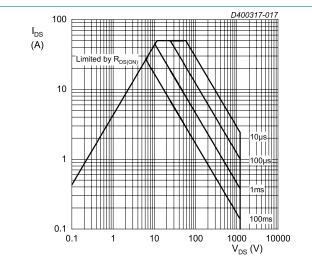


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



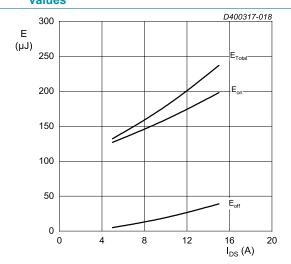
 $V_{DS} = 0 - 1000 V$ 



 $T_i = 25 \,^{\circ}C; D = 0$ Parameter: t₀

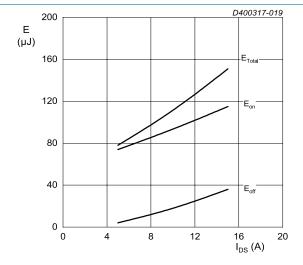
 $T_j = 25$  °C;  $V_{AC} = 25$  mV; f = 1 MHz Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

Fig. 17. Forward bias safe operating area



 $T_{j}$  = 25 °C;  $V_{DD}$  = 800 V;  $R_{G(ext)}$  = 5.1  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 330  $\mu H$ FWD = WNSC2M150120TB

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



 $T_{j}$  = 25 °C;  $V_{DD}$  = 600 V;  $R_{G(ext)}$  = 5.1  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 330  $\mu H$ FWD = WNSC2M150120TB

Fig. 19. Clamped Inductive Switching Energy as a function of drain current

D400317-021

 $E_{Total}$ 

Eon

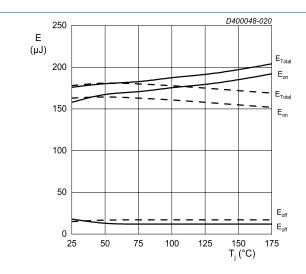
 $E_{off}$ 

 $R_{G(ext)}^{-}(\Omega)$ 

25

20

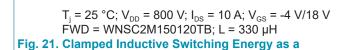
#### **N-Channel Silicon Carbide MOSFET**



 $I_{DS}$  = 10 A;  $V_{DD}$  = 800 V;  $R_{G(ext)}$  = 5.1  $\Omega;$   $V_{GS}$  = -4 V/18 V; L = 330  $\mu H$ 

FWD = WNSC2M150120TB

FWD = WNSC2D201200TB(---)



function of external gate resistance

300

250

200

150

100

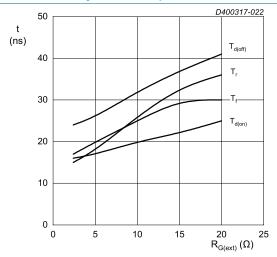
50

0

Е

(µJ)





 $T_{j}$  = 25 °C;  $V_{DD}$  = 800 V;  $I_{DS}$  = 10 A;  $V_{GS}$  = -4 V/18 V FWD = WNSC2M150120TB; L = 330  $\mu$ H

Fig. 22. Switching time as a function of external gate resistance

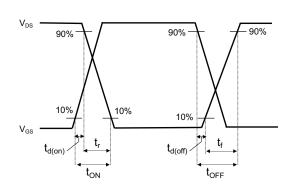
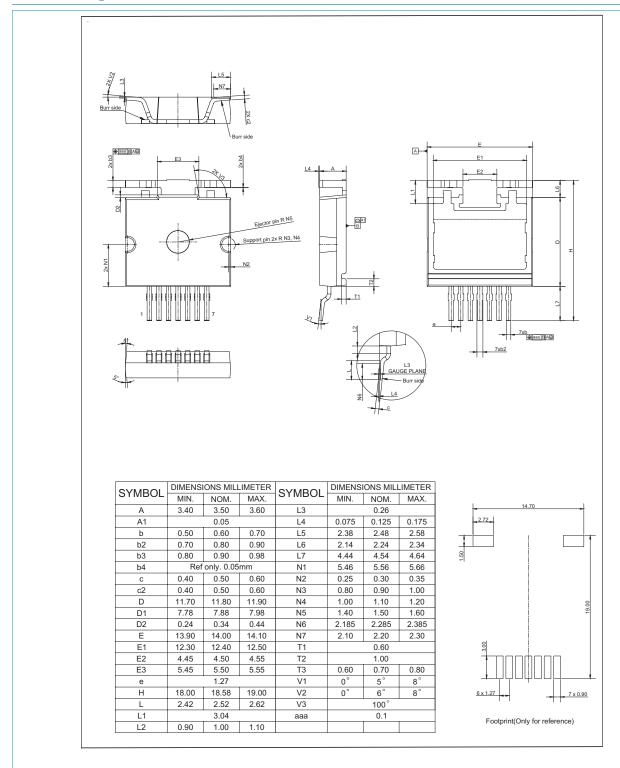


Fig. 23. Switching time definition

## 11. Package outline



**Product data sheet** 

## 12. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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# WNSC2M150120TB

**N-Channel Silicon Carbide MOSFET** 

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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 18 November 2024

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